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2 ABSTRACT

3 The present invention bundles four ring oscillators, a 20-bit ripple counter and the necessary
4 control logic needed to implement a JTAG scan based interface. The present system can be located
5 on every die, so that each location can be individually tested. It communicates with the outside world
6 through a standard JTAG interface. It is accessible at wafer, package, and system test which allows
7 for several methods of correlating the oscillator speed to the speed of a part in the actual system.
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